

STD100NH02L STD100NH02L-1

N-channel 24V - 0.0042Ω - 60A - DPAK - IPAK STripFET™ II Power MOSFET

General features

Туре	V_{DSSS}	R _{DS(on)}	I _D
STD100NH02L	24V	<0.0048Ω	60A ⁽¹⁾
STD100NH02L-1	24V	<0.0048Ω	60A ⁽¹⁾

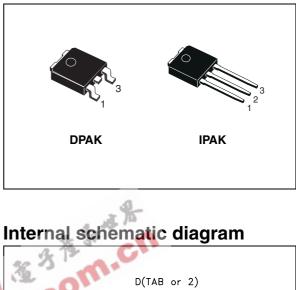
- 1. Value limited by wire bonding
- R_{DS(on)} * Qg industry's benchmark
- Conduction losses reduced
- Switching losses reduced
- Low threshold device

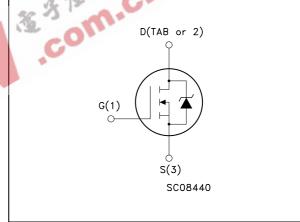
Description

This device utilizes the latest advanced design rules of ST's proprietary STripFET[™] technology. This is suitable fot the most demanding DC-DC converter application where high efficiency is to be achieved.

Applications

Switching application





Order codes

Part number	Marking	Package	Packaging
STD100NH02LT4	D100NH02L	DPAK	Tape & reel
STD100NH02L-1	D100NH02L	IPAK	Tube

August 2006

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Electrical ratings

Table 1.	Absolute	maximum	ratings
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Symbol	Parameter	Value	Unit
V _{spike} ⁽¹⁾	Drain-source voltage rating	30	V
V _{DS}	Drain-source voltage (V _{GS} = 0)	24	V
V _{DGR}	Drain-gate voltage ($R_{GS} = 20K\Omega$)	24	V
V _{GS}	Drain-source voltage	± 20	V
I _D ⁽²⁾	Drain current (continuous) at $T_{C} = 25^{\circ}C$	60	А
I _D ⁽²⁾	Drain current (continuous) at T _C =100°C	60	А
I _{DM} ⁽³⁾	Drain current (pulsed)	240	А
P _{TOT}	Total dissipation at $T_{C} = 25^{\circ}C$	100	W
	Derating factor	0.67	W/°C
E _{AS} ⁽⁴⁾	Single pulse avalanche energy	800	mJ
T _{stg}	Storage temperature	-55 to 175	.0°
TJ	Max. operating junction temperature	-55 10 175	
 Value Pulse v 	ed when external Rg = 4.7 Ω and $t_f < t_{fmax}$. limited by wire bonding. width limited by safe operating area g T _J = 25 °C, I _D = 30A, V _{DD} = 15V	com.C	

Table 2. Thermal data

Symbol	Parameter	Value	Unit
R _{thJC}	Thermal resistance junction-case Max	1.5	°C/W
R _{thJA}	Thermal resistance junction-ambient Max	100	°C/W
т _і	Maximum lead temperature for soldering purpose	275	°C



Electrical characteristics 2

(T_{CASE}=25°C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 25mA, V _{GS} = 0	24			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	$V_{DS} = 20$ $V_{DS} = 20, T_{C} = 125^{\circ}C$			1 10	μΑ μΑ
I _{GSS}	Gate body leakage current (V _{DS} = 0)	$V_{GS} = \pm 20V$			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1	1.8		V
R _{DS(on)}	Static drain-source on resistance	$V_{GS} = 10V, I_D = 30A$ $V_{GS} = 5V, I_D = 15A$		0.0042 0.005	0.0048 0.09	Ω Ω

Table 3. **On/off states**

Table 4. Dvnamic

		G3 - , D -				
Table 4.	Dynamic	2 10 35	4			1
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
9 _{fs} ⁽¹⁾	Forward transconductance	V _{DS} = 10 V _, I _D = 30A		50		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 15V, f = 1 MHz, V _{GS} = 0		3940 1020 110		pF pF pF
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V _{DD} = 10V, I _D = 30A V _{GS} = 10V		62 12 8	84	nC nC nC
Q _{oss} ⁽²⁾	Output charge	$V_{DS} = 16V, V_{GS} = 0V$		24		nC
Q _{gls} ⁽³⁾	Third-quadrant gate charge	V_{DS} < 0V, V_{GS} = 10V		56.5		nC
R _G	Gate input resistance	f = 1MHz gate DC Bias = 0 Test signal level = 20mV Open drain		1.1		Ω

1. Pulsed: pulse duration=300µs, duty cycle 1.5%

2. $Q_{oss} = C_{oss}^* \Delta V_{in}$, $C_{oss} = C_{gd} + C_{ds}$. See *Chapter Appendix A*

3. Gate charge for synchronous operation



	ownoning times					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r t _{d(off)} t _f	Turn-on delay time Rise time Turn-off delay time Fall time	$V_{DD} = 10V, I_D = 30A,$ $R_G = 4.7\Omega, V_{GS} = 10V$ <i>Figure 13 on page 8</i>		15 200 60 35	47	ns ns ns ns

Table 5. Switching times

Table 6. Source drain diode

Symbol	Parameter	Test conditions	Min	Тур.	Max	Unit
I _{SD}	Source-drain current				60	А
I _{SDM}	Source-drain current (pulsed)				240	А
V _{SD} ⁽¹⁾	Forward on voltage	$I_{SD} = 30A, V_{GS} = 0$			1.3	V
t _{rr} Q _{rr} I _{RRM} 1. Pulsed: p	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} = 60A, di/dt = 100A/μs, V _{DD} = 15V, T _J = 150°C <i>Figure 15 on page 8</i>		47 58 2.5		ns μC Α



GC94520

 $Z_{th} = k R_{thJ-c}$

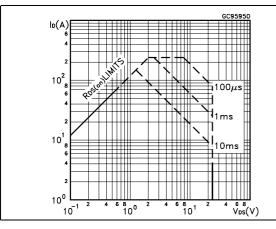
 $10^{-1} t_{P}(s)$

 $\delta = t_p / \tau$

10⁻²

Electrical characteristics (curves) 2.1

Figure 1. Safe operating area







10⁻⁴

SINGLE PULSE

Thermal impedance

0.02

0.01

10⁻³

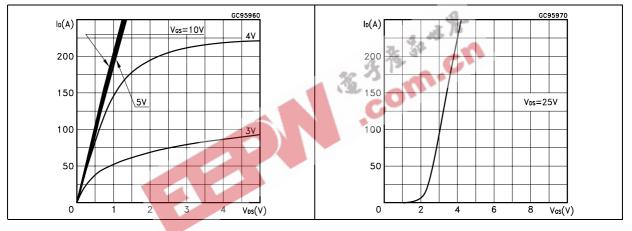


Figure 2.

280TOAI

к

10

10

10⁻⁵



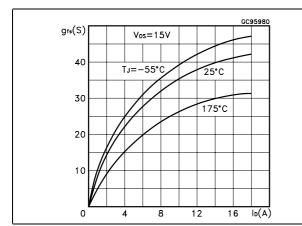
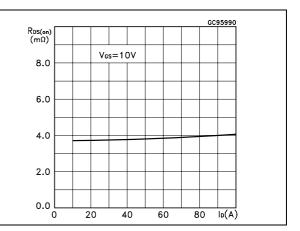
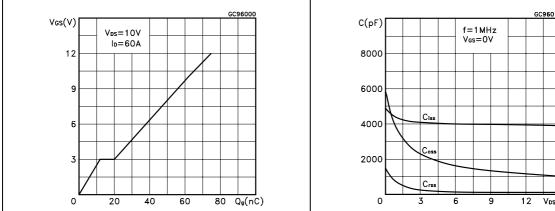


Figure 6. Static drain-source on resistance





Gate charge vs gate-source voltage Figure 8. Capacitance variations Figure 7.

Figure 9. Normalized gate threshold voltage vs temperature

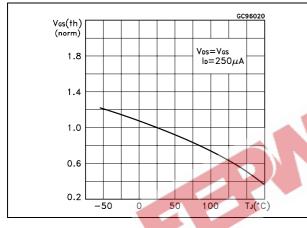


Figure 11. Source-drain diode forward characteristics

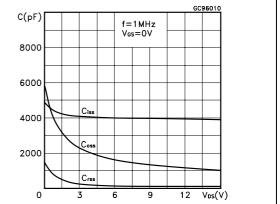


Figure 10. Normalized on resistance vs temperature

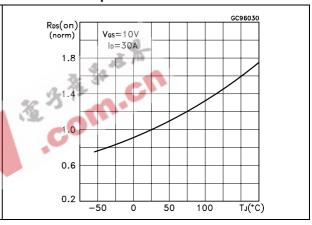
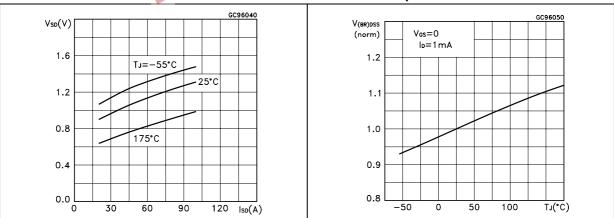
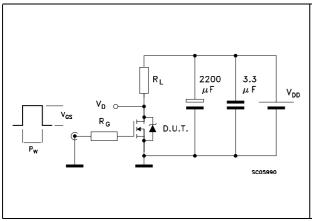


Figure 12. Normalized breakdown voltage vs temperature



3 Test circuit

Figure 13. Switching times test circuit for resistive load



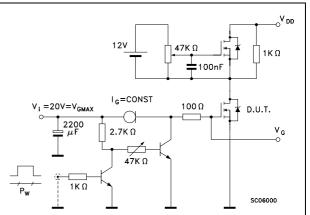
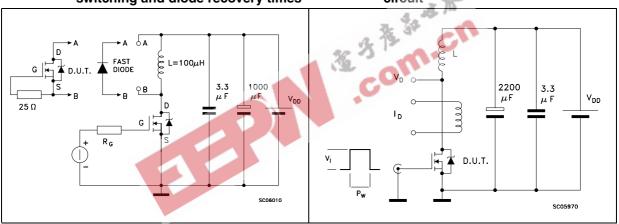
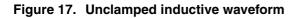


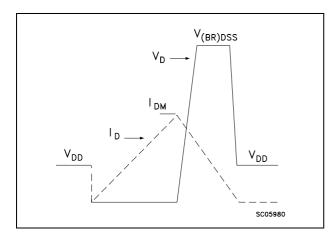
Figure 14. Gate charge test circuit

Figure 15. Test circuit for inductive load switching and diode recovery times

Figure 16. Unclamped Inductive load test circuit







4 Package mechanical data

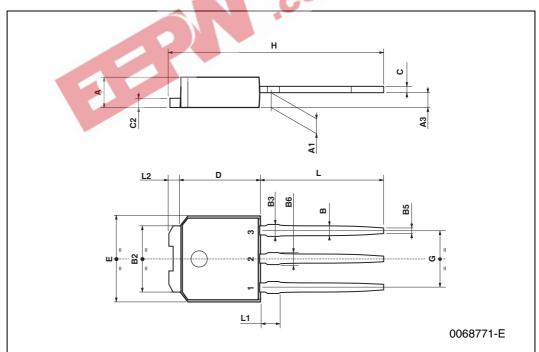
In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com



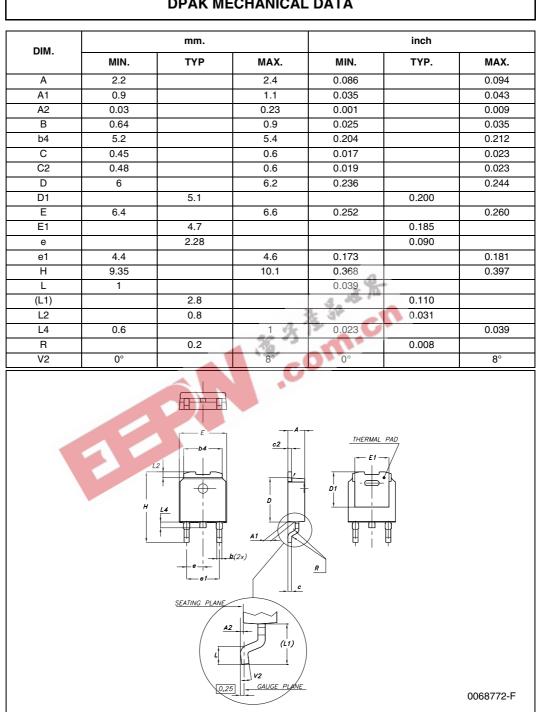


		mm		inch		
DIM.	MIN.	ТҮР.	MAX.	MIN.	ТҮР.	MAX.
А	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A3	0.7		1.3	0.027		0.051
В	0.64		0.9	0.025		0.031
B2	5.2		5.4	0.204		0.212
B3			0.85			0.033
B5		0.3			0.012	
B6			0.95			0.037
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
E	6.4		6.6	0.252		0.260
G	4.4		4.6	0.173		0.181
Н	15.9		16.3	0.626		0.641
L	9		9.4	0.354	1 m	0.370
L1	0.8		1.2	0.031		0.047
L2		0.8	1		0.031	0.039

TO-251 (IPAK) MECHANICAL DATA







DPAK MECHANICAL DATA

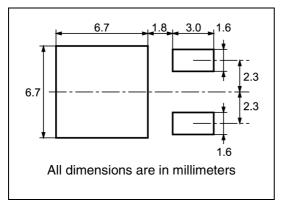


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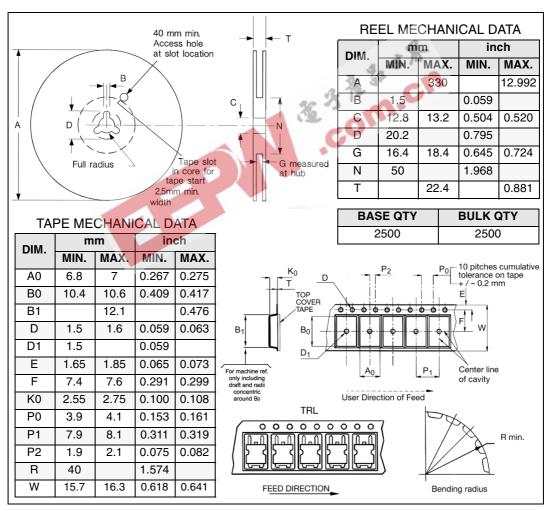
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Packaging mechanical data

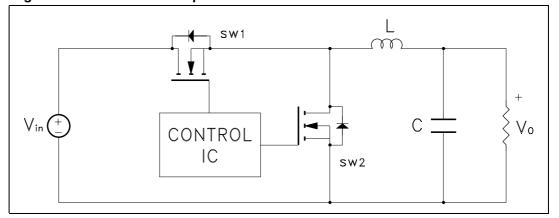
DPAK FOOTPRINT



TAPE AND REEL SHIPMENT



Appendix A Buck converter - power losses estimation





The power losses associated with the FETs in a synchronous buck converter can be estimated using the equations shown in the table below. The formulas give a good approximation, for the sake of performance comparison, of how different pairs of devices affect the converter efficiency. However a very important parameter, the working temperature, is not considered. The real device behavior is really dependent on how the heat generated inside the devices is removed to allow for a safer working junction temperature.

- The low side (SW2) device requires:
- Very low R_{DS(on)} to reduce conduction losses
- Small QgIs to reduce the gate charge losses
- Small Coss to reduce losses due to output capacitance
- Small Qrr to reduce losses on SW1 during its turn-on
- The Cgd/Cgs ratio lower than Vth/Vgg ratio especially with low drain to source
- voltage to avoid the cross conduction phenomenon;
- The high side (SW1) device requires:
- Small Rg and Ls to allow higher gate current peak and to limit the voltage feedback on the gate
- Small Qg to have a faster commutation and to reduce gate charge losses
- Low R_{DS(on)} to reduce the conduction losses.



		High side switching (SW1)	Low side switch (SW2)
Pconc	duction	$R_{DS(on)SW1} * I_L^2 * \delta$	$R_{DS(on)SW2} * I_L^2 * (1 - \delta)$
Pswit	tching	$V_{in} * (Q_{gsth(SW1)} + Q_{gd(SW1)}) * f * \frac{I_L}{I_g}$	Zero Voltage Switching
Pdiode	Recovery	Not applicable	$V_{in} * Q_{rr(SW2)} * f$
	Conductio n	Not applicable	$V_{f(SW2)} * I_L * t_{deadtime} * f$
Pgate	e(Q _G)	$Q_{g(SW1)} * V_{gg} * f$	$Q_{gls(SW2)} * V_{gg} * f$
PG	Qoss	$\frac{V_{in} * Q_{oss(SW1)} * f}{2}$	$\frac{V_{in} * Q_{oss(SW2)} * f}{2}$
Dissipated	d by SW1 durir	ng turn-on	

Table 7. Power losses calculation

Paramiters meaning Table 8.

Parameter	Meaning		
d	Duty-cycle		
Q _{gsth}	Post threshold gate charge		
Q _{gls}	Third quadrant gate charge		
Pconduction	On state losses		
Pswitching	On-off transition losses		
Pdiode	Conduction and reverse recovery diode losses		
Pgate	Gate drive losses		
P _{Qoss}	Output capacitance losses		



6 Revision history

Date	Revision	Changes
09-Sep-2004	9	Complete version
08-Aug-2006	10	New template, updated SOA





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